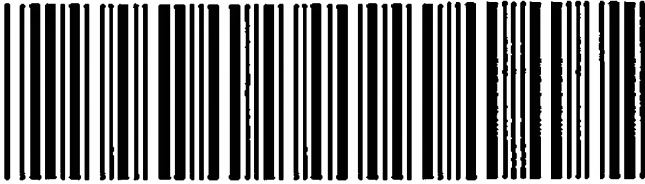


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/619,566	TANABE, TAKAHISA	
	Examiner	Art Unit	
	Sara W. Crane	2811	

SEARCHED			
Class	Subclass	Date	Examiner
257	40	12/05	SWC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR